


<b>Search Notes</b> 	<b>Application/Control No.</b> 10820011	<b>Applicant(s)/Patent Under Reexamination</b> YEW ET AL.
	<b>Examiner</b> Chang, Rick K	<b>Art Unit</b> 3726

SEARCHED			
Class	Subclass	Date	Examiner
29	848,849,832,840	12/22/06	rc
156	233		
438	26,22,106,127		

SEARCH NOTES		
Search Notes	Date	Examiner
east search	12/22/06	rc
reviewed parent case and references cited therein		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner